

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/762,031	YUEH ET AL
Examiner	Art Unit	
John S. Chu	1752	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
430	168	9/2005	JLR
430	190		
430	193		
430/326			